## Application/Control No. Applicant(s)/Patent Under Reexamination YAMAOKA ET AL. Examiner Jon Chang Applicant(s)/Patent Under Reexamination YAMAOKA ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

_	O.O. I. ALEXT BOOOMERTO										
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification						
	Α	US-6,094,507	07-2000	Monden, Akira	382/195						
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## **NON-PATENT DOCUMENTS**

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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